



Subject card

Subject name and code	Microscopy methods in nanotechnology, PG_00071199						
Field of study	Nanotechnology						
Date of commencement of studies	October 2026	Academic year of realisation of subject			2026/2027		
Education level	second-cycle studies	Subject group			Obligatory subject group in the field of study Subject group related to scientific research in the field of study		
Mode of study	Full-time studies	Mode of delivery			at the university		
Year of study	1	Language of instruction			English		
Semester of study	1	ECTS credits			2.0		
Learning profile	general academic profile	Assessment form			assessment		
Conducting unit	Division of New Functional Materials For Energy Conversion -> Institute of Nanotechnology and Materials Engineering -> Faculty of Applied Physics and Mathematics -> Faculties of Gdańsk University of Technology						
Name and surname of lecturer (lecturers)	Subject supervisor	dr hab. inż. Jakub Karczewski					
	Teachers						
Lesson types	Lesson type	Lecture	Tutorial	Laboratory	Project	Seminar	SUM
	Number of study hours	10.0	0.0	15.0	0.0	0.0	25
	E-learning hours included: 0.0						
Learning activity and number of study hours	Learning activity	Participation in didactic classes included in study plan	Participation in consultation hours	Self-study	SUM		
	Number of study hours	25	1.0	24.0	50		
Subject objectives	Understanding modern methods of imaging nanostructures.						
Learning outcomes	Course outcome	Subject outcome		Method of verification			
	[K7_U04] is able to formulate hypotheses, plan and conduct experimental research, critically analyze results, verify hypotheses, draw conclusions, and formulate well-founded opinions within nanotechnology and related physical and natural sciences. Recognizes economic and non-technical aspects of the activities performed	The student is able to prepare perform and interpret experiment in the field modern imaging methods.		[SU1] Assessment of task fulfilment [SU2] Assessment of ability to analyse information [SU5] Assessment of ability to present the results of task			
	[K7_W04] has theoretical and practical knowledge of physical and chemical experimental methods in nanotechnology and understands the principles of their application in processes occurring throughout the life cycle of technical systems	The student has knowledge of modern microscopic methods. The student knows, understands and can perform measurements using SEM, AFM, STM microscopy.		[SW1] Assessment of factual knowledge			

Subject contents	Course content – lecture		
	<ul style="list-style-type: none"> • optical microscopy • tunneling microscopy • atomic force microscopy • scanning electron microscopy • transmission electron microscopy 		
	Course content – laboratory		
	<ul style="list-style-type: none"> • sample preparation and measurements using AFM microscopy • AFM image analysis • sample preparation and measurements using SEM microscopy • preparation and imaging of the selected research object 		
Prerequisites and co-requisites	Basic physics knowledge.		
Assessment methods and criteria	Subject passing criteria	Passing threshold	Percentage of the final grade
	lecture exam	50.0%	50.0%
	laboratory work report	50.0%	50.0%
Recommended reading	Basic literature	<ul style="list-style-type: none"> • Weillie Zhou Zhong Lin Wang "Scanning Microscopy for Nanotechnology Techniques and Applications" Springer 2007 • V. L. Mironov "Fundamentals of Scanning Probe Microscopy" NT-MDT 2004 	
	Supplementary literature	<ul style="list-style-type: none"> • Nanosurf easyScan 2 - operating instruction 	
	eResources addresses		
Example issues/ example questions/ tasks being completed	<ul style="list-style-type: none"> • principle of atomic force microscopy • imitations of the SEM microscopy • comparison of imaging methods of nanostructures 		
Practical activities within the subject	Not applicable		

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